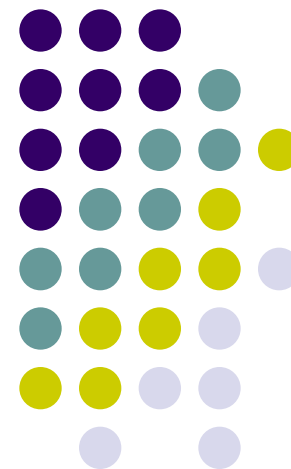
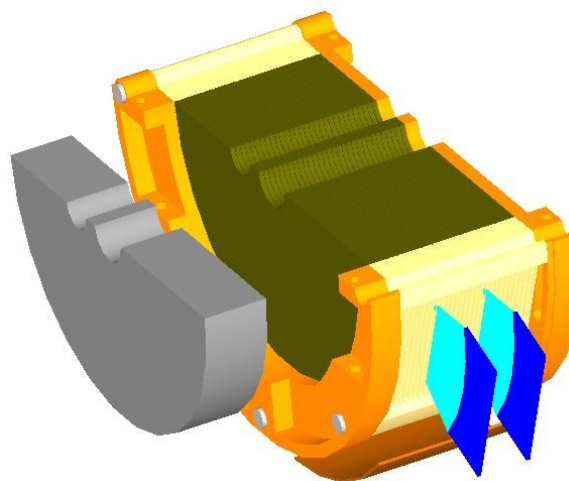


Sapphire sensors for BeamCal



Sergej Schuwalow, DESY Hamburg

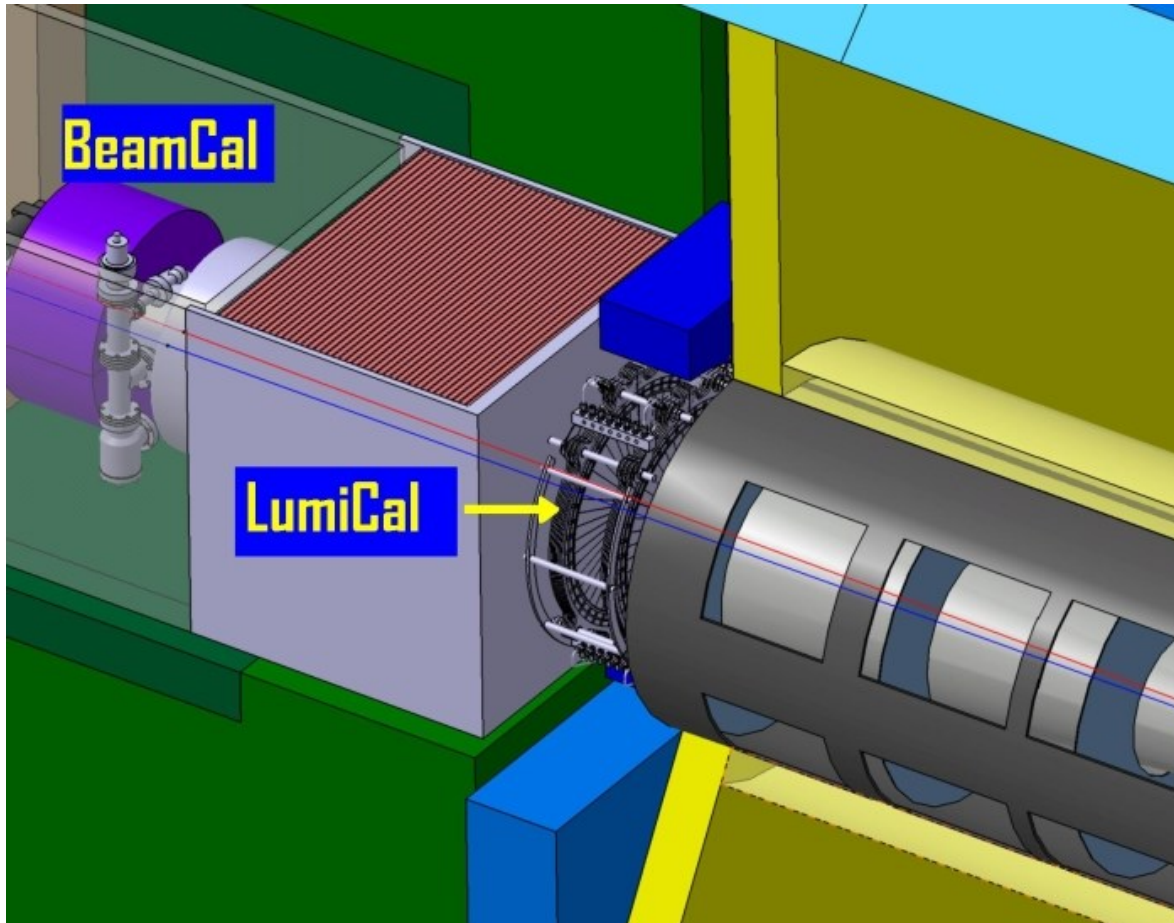




Contents

- BeamCal sensor requirements
- Sapphire (Al_2O_3) properties (+diamond, GaAs, Si)
- Synthesis of sapphire
- Radiation hardness
- Application at FLASH, signal shape
- Charge collection efficiency
- Detection of MIPs with sapphire sensors
- BeamCal sensor configurations
- First simulation results
- Conclusions and outlook

BeamCal sensor requirements



BeamCal should be compact,
small Moliere radius needed:
- sampling calorimeter
with solid state sensors,
tungsten as absorber.

Severe load at small radii
due to beamstrahlung:
- radiation hard sensors
(up to 1 MGy annual dose)

Bunch-by-bunch operation:
- fast response of sensors

Test beam studies, physical
calibration:
- sensitivity to MIPs

Sensor material properties



	Sapphire	Diamond	GaAs	Si
• Density, g/cm ³	3.98	3.52	5.32	2.33
• Dielectric constant	9.3 - 11.5	5.7	10.9	11.7
• Breakdown field, V/cm	$\sim 10^6$ *	10^7	$4 \cdot 10^5$	$3 \cdot 10^5$
• Resistivity, $\Omega \cdot \text{cm}$	$> 10^{14}$	$> 10^{11}$	10^7	10^5
• Band gap, eV	9.9	5.45	1.42	1.12
• El. mobility, cm ² /(V·s)	> 600 **	1800	~ 8500	1360
• Hole mobility, cm ² /(V·s)	-	1200	-	460
• MIP eh pairs created, eh/ μm	22	36	150	73

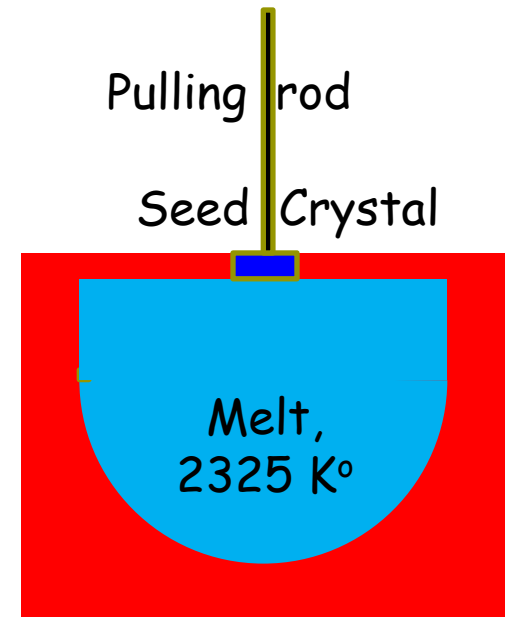
* Typical operation field $\sim 1\text{-}2 \cdot 10^4 \text{ V cm}^{-1}$

** at 20°C, ~ 30000 at 40°K



Synthesis of sapphire (Al_2O_3)

- Single crystals are grown by Czochralski process
- Growing speed ~ 100 mm/hour
- Up to 440 mm diameter crystals
- Crystal weight up to ~ 500 Kg
- World annual production > 250 tons
- Used in chemistry, electronics, semiconductor industry, lasers, etc.



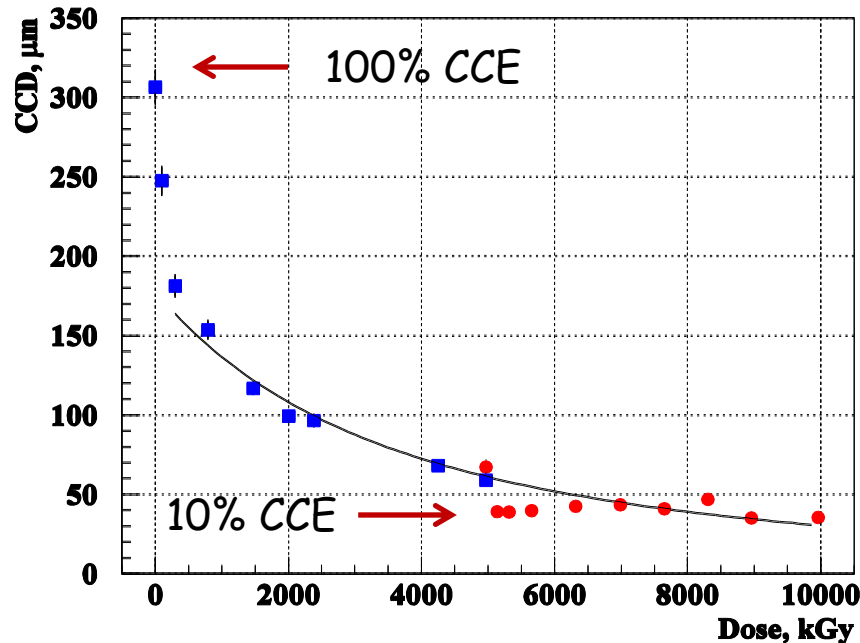
Impurity	Na	Si	Fe	Ca	Mg	Ni	Ti	Mn	Cu	Zr	Y
ppm	8	2	5	5	1	<3	<1	3	<3	2	2

Irradiation of sapphire and diamond sensors at ~10 MeV electron beam



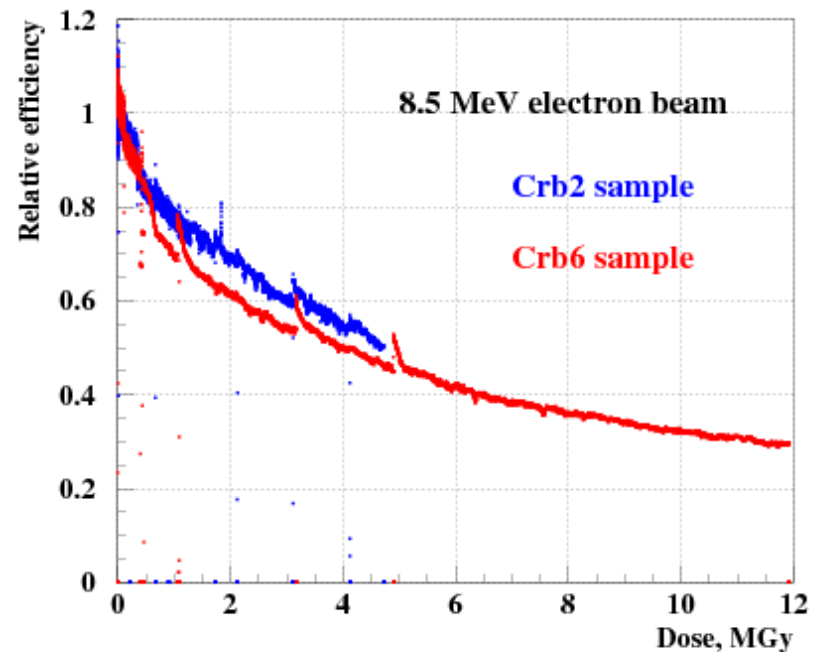
Single crystal CVD diamond

So14_04 scCVD Diamond Irradiation



Single crystal sapphire

Irradiation of sapphire samples



Leakage current after irradiation is still at few pA level

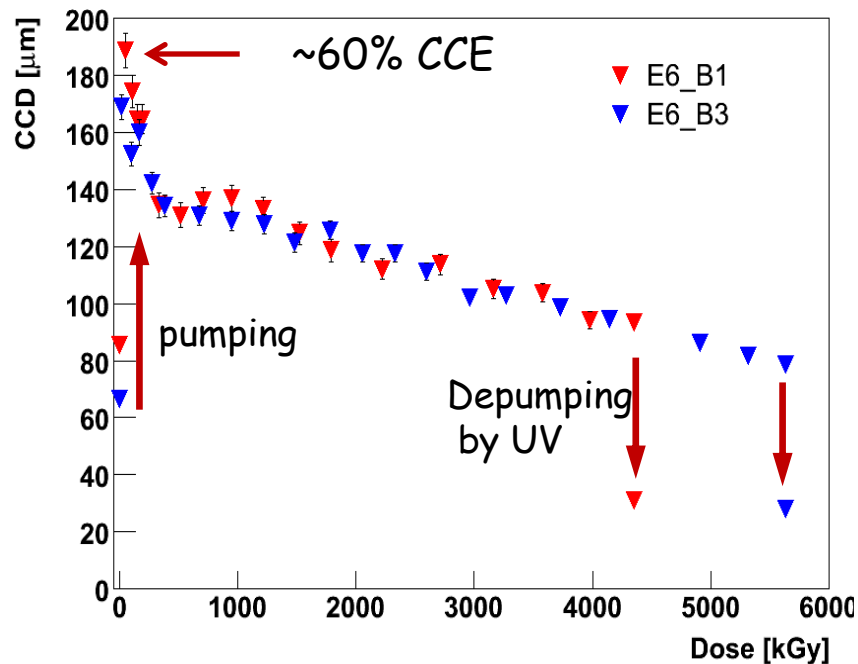
$10 \text{ MGy} \sim 5 \cdot 10^{16} \text{ MIPs} \sim 2.5 \cdot 10^{15} [1 \text{ MeV neq}]$ (NIEL, Summers)

Irradiation of sapphire and diamond sensors at ~10 MeV electron beam



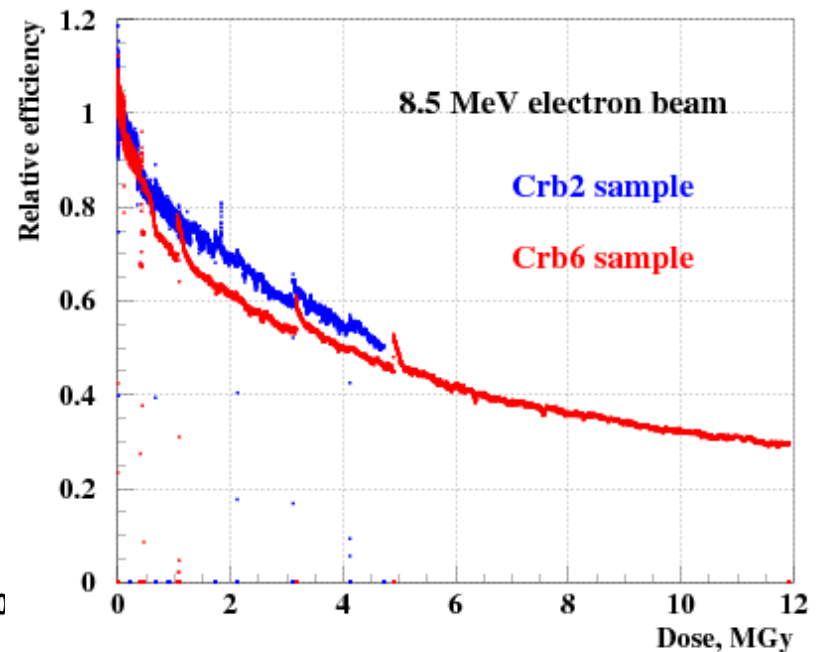
Polycrystalline CVD diamond

E6 samples CCD vs dose at 400V



Single crystal sapphire

Irradiation of sapphire samples

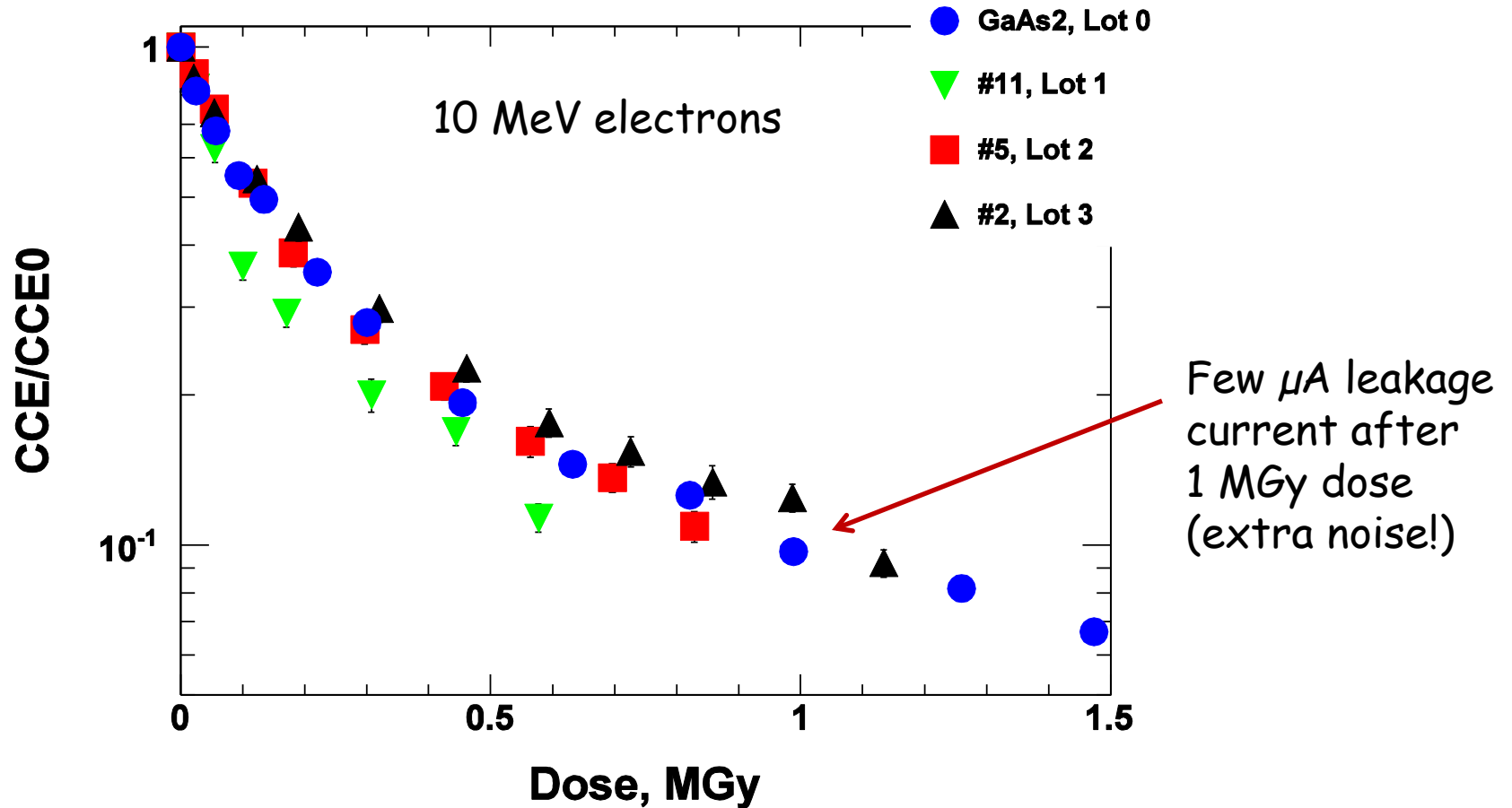


Leakage current after irradiation is still at few pA level

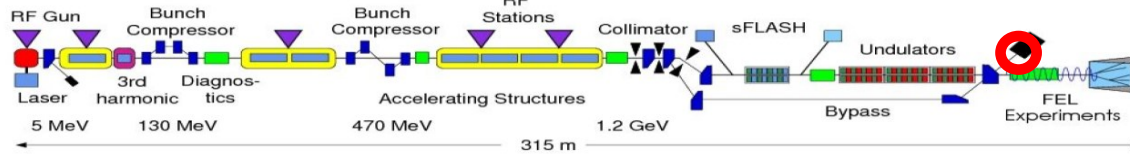
$10 \text{ MGy} \sim 5 \cdot 10^{16} \text{ MIPs} \sim 2.5 \cdot 10^{15} [1 \text{ MeV neq}]$ (NIEL, Summers)



Irradiation of GaAs sensors

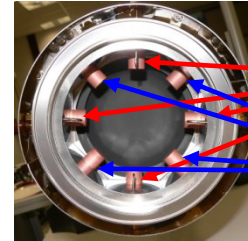


Beam Halo Monitor at FLASH



4 artificial sapphire sensors

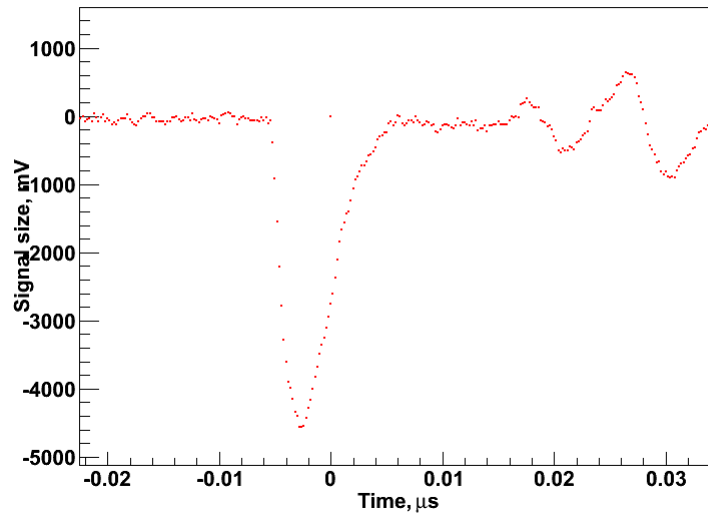
4pCVD diamond sensors



Sapphire sensors

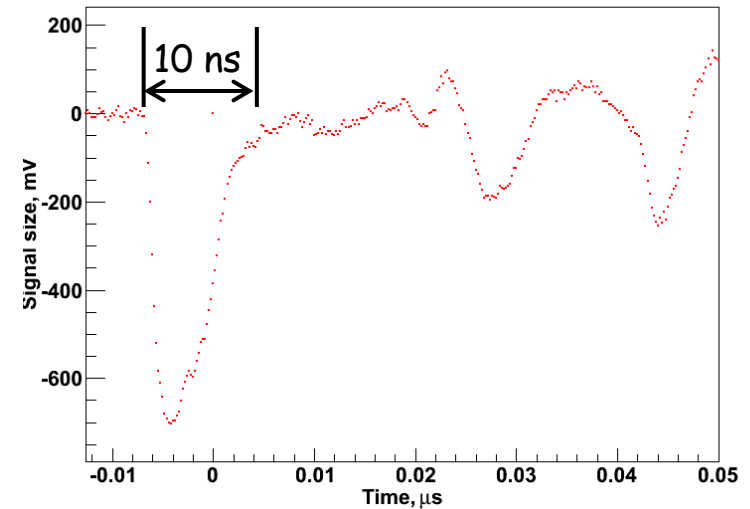
Diamond sensors

DL signal 50 Ohm



Analog signal from diamond sensor

U signal 50 Ohm, 500pC, 20 dB



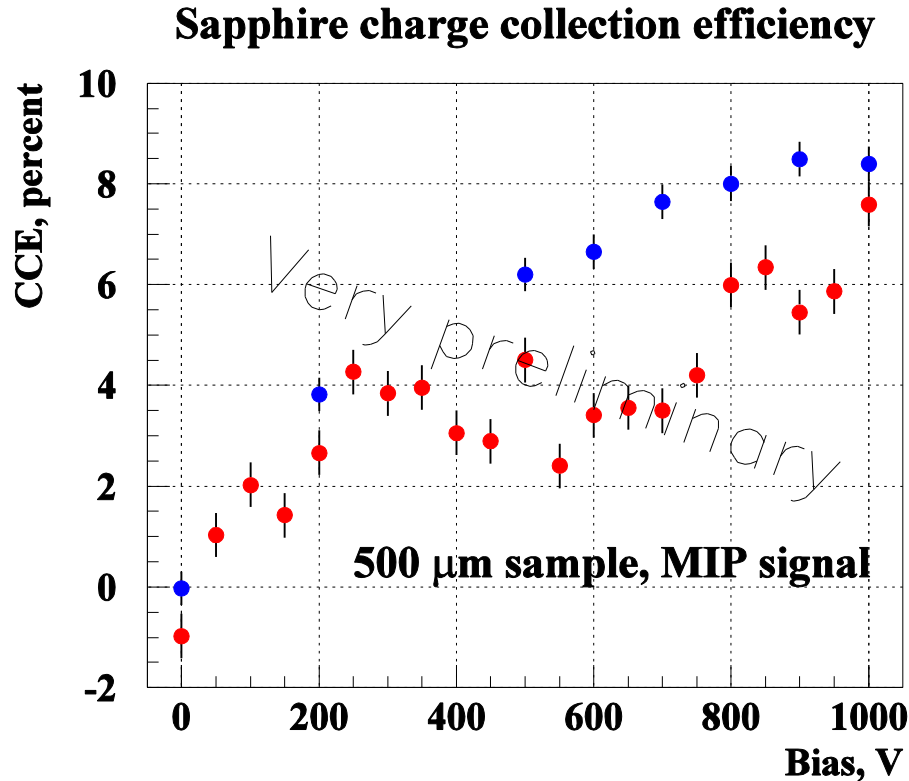
Analog signal from sapphire sensor

A.Ignatenko, DESY-HH

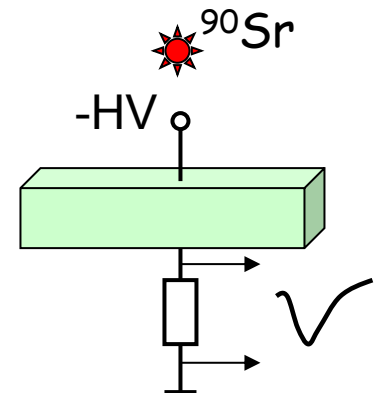
25th FCAL workshop, Belgrade

Sapphire charge collection efficiency

Measured at ^{90}Sr setup

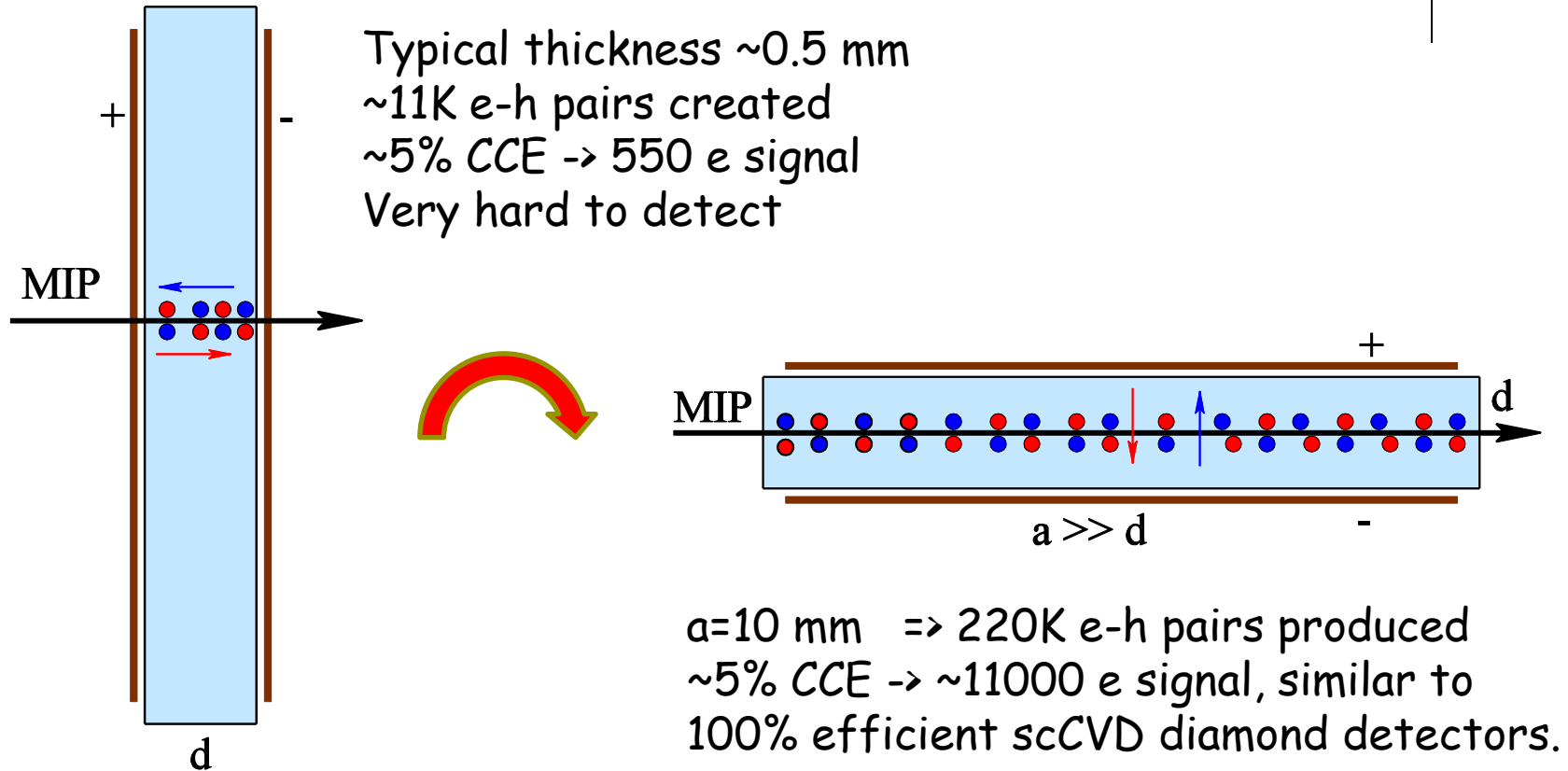


Signal $\sim 600 e^-$





Detection of MIPs

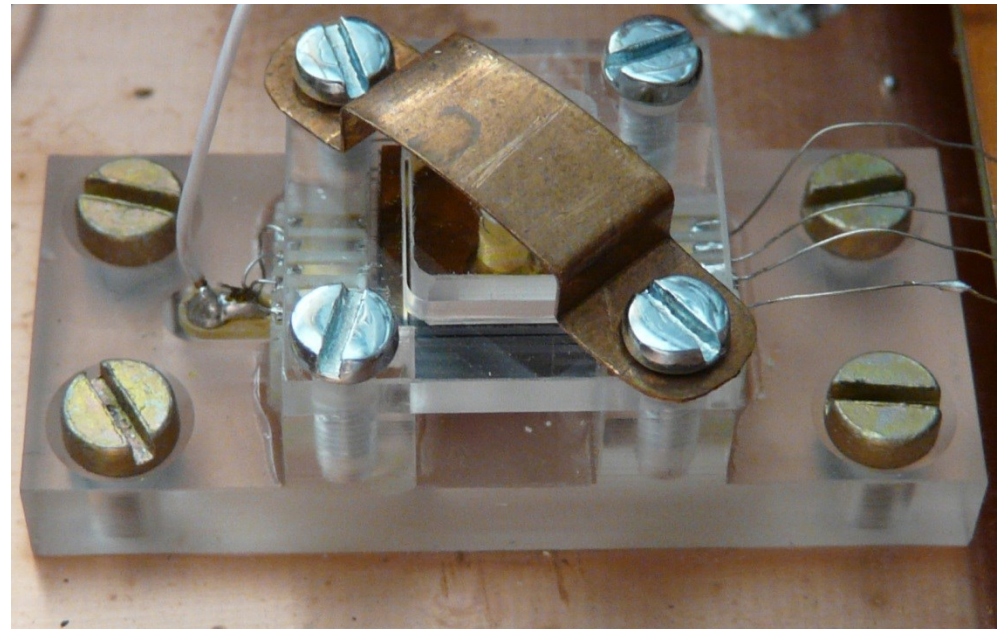
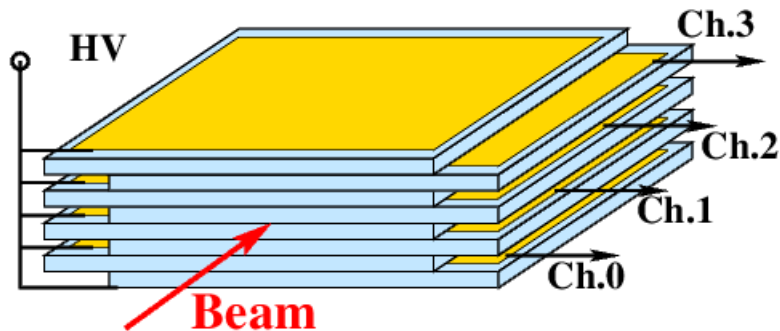
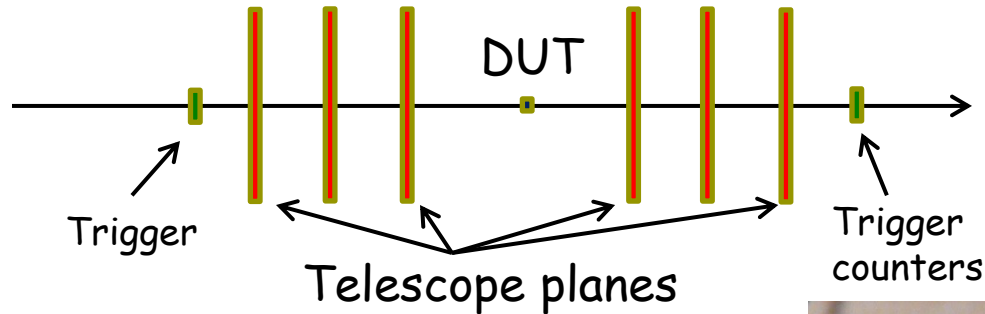


Test beam 2014, DESY

Stack of 8 sapphire plates

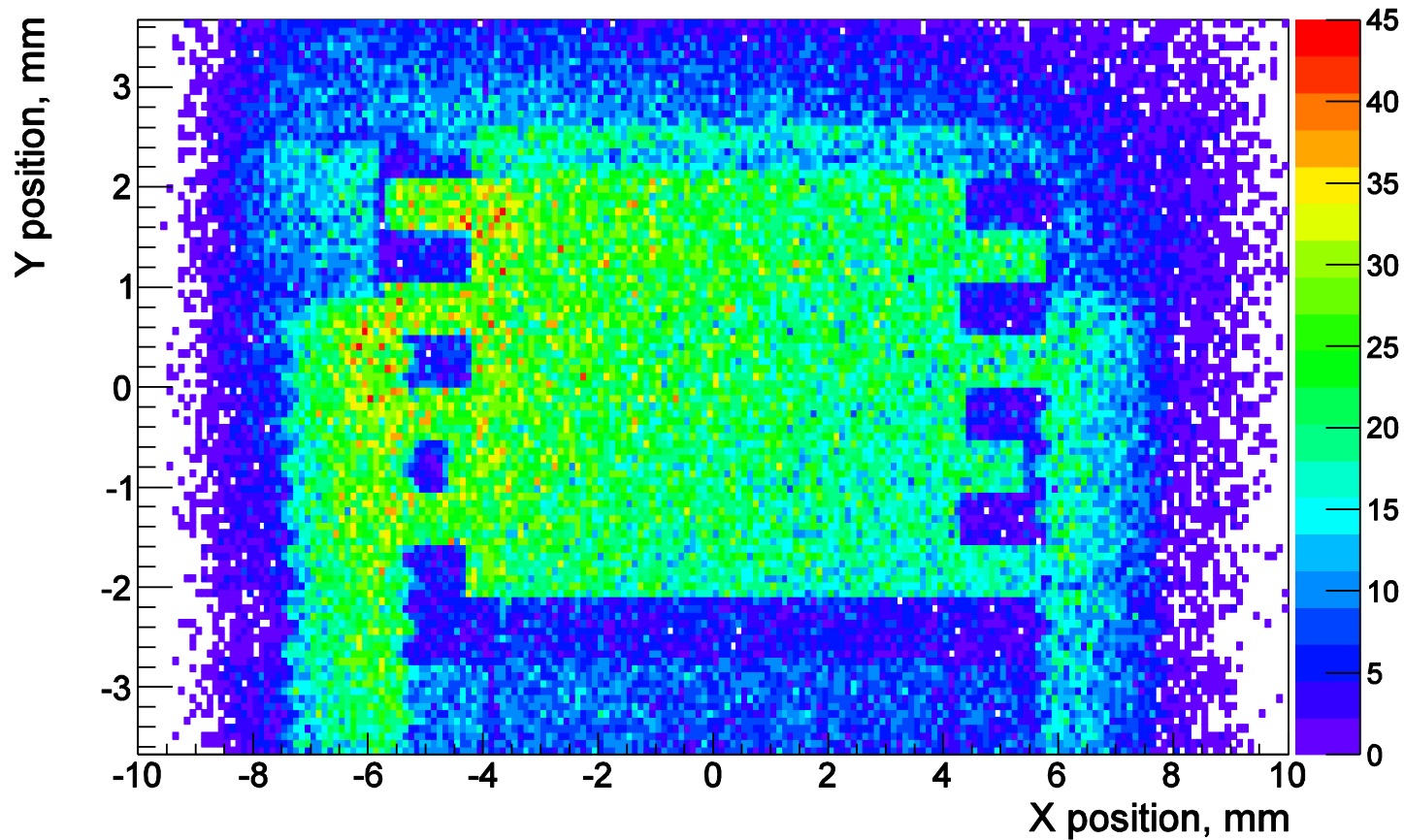


- 5 GeV electrons + EUDET pixel telescope

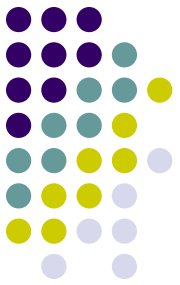


Stack image, scattered tracks

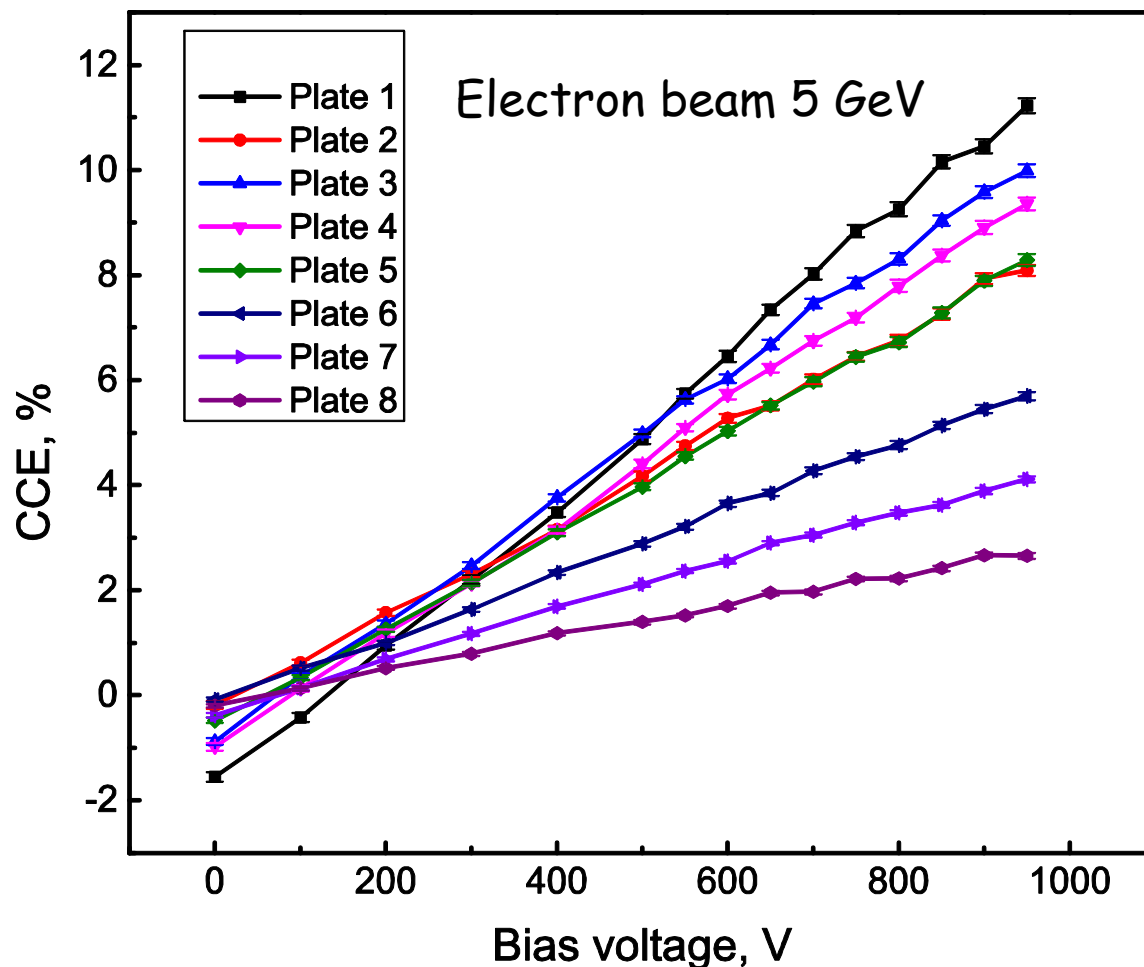
Sapphire detector image, constructed from scattered tracks, $Z=0$



Resolution $\sim 10 \mu\text{m}$



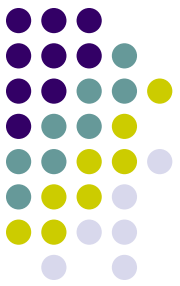
Sapphire charge collection efficiency



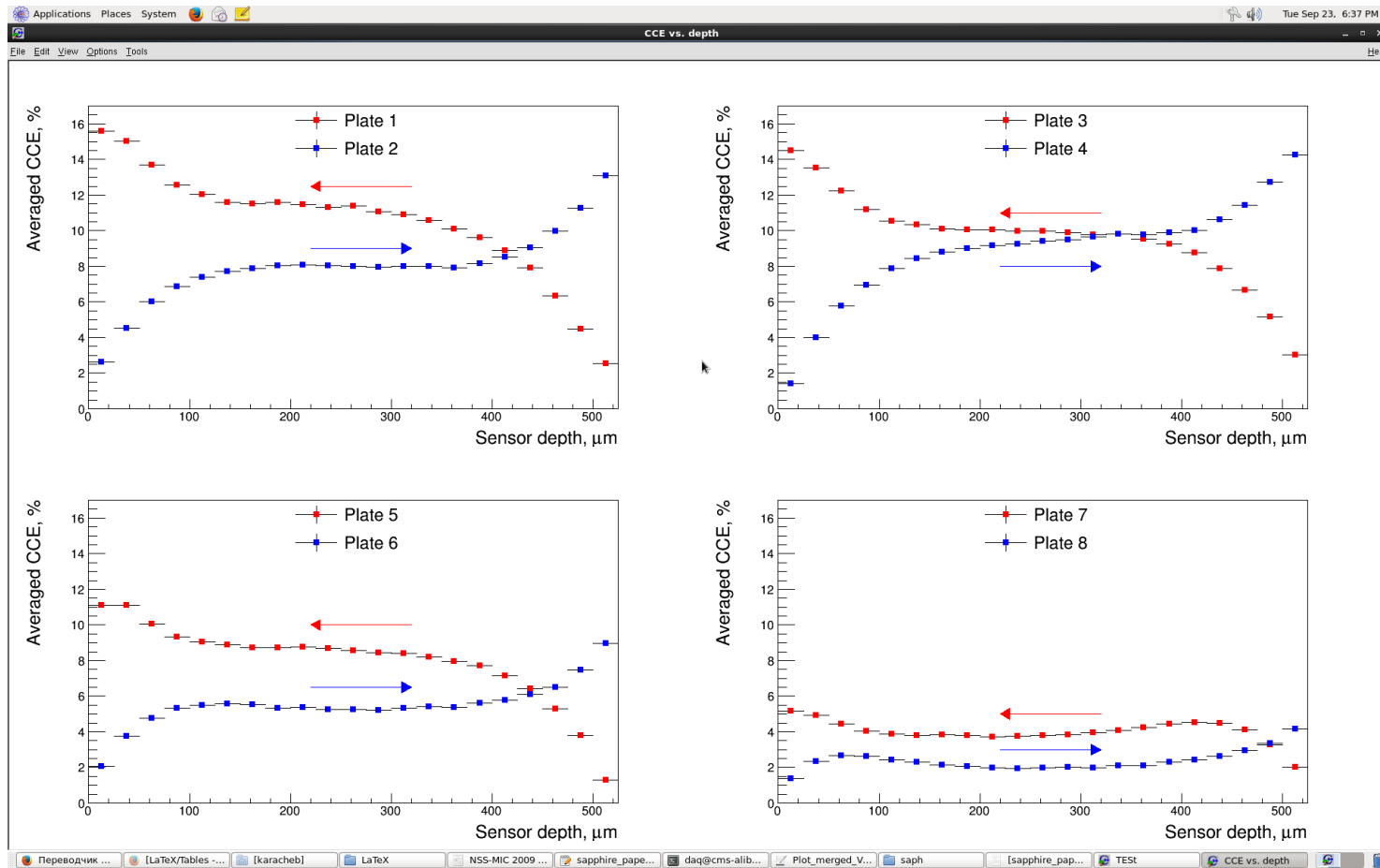
CCE linearly depends
on the field strength

CCE for good plates
~5% at 1 V/ μm

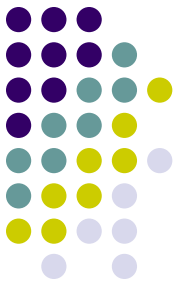
CCE as a function of sensor depth



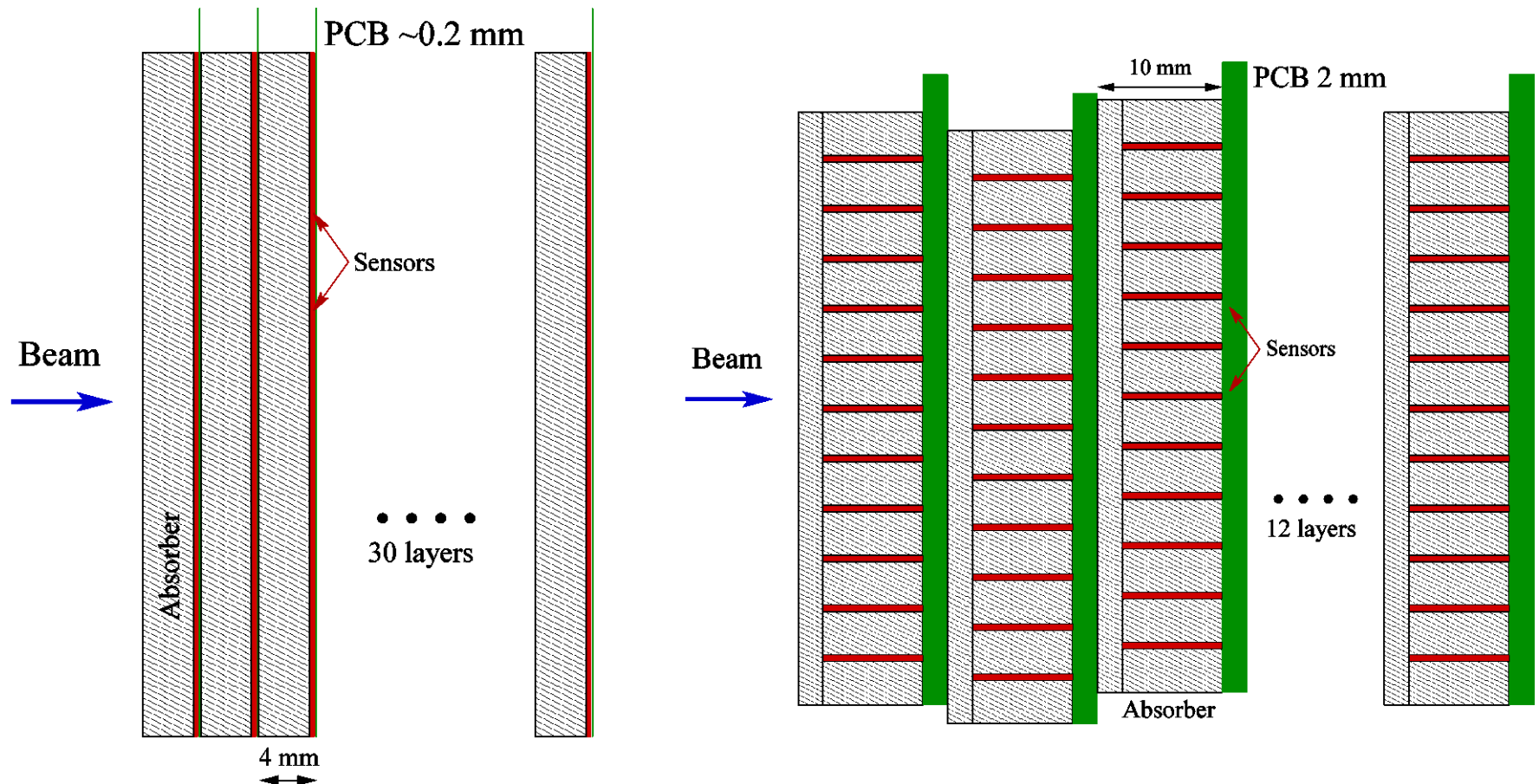
Electron beam 5 GeV



Charge collection by electrons only
Indication to the presence of polarization field



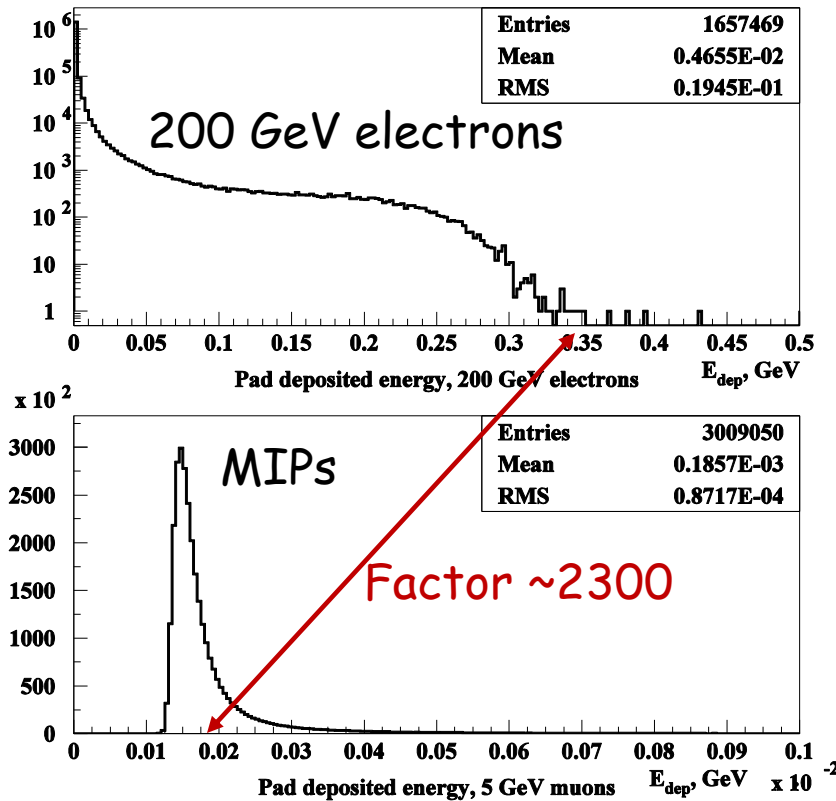
Modification of BeamCal design for sapphire sensors application



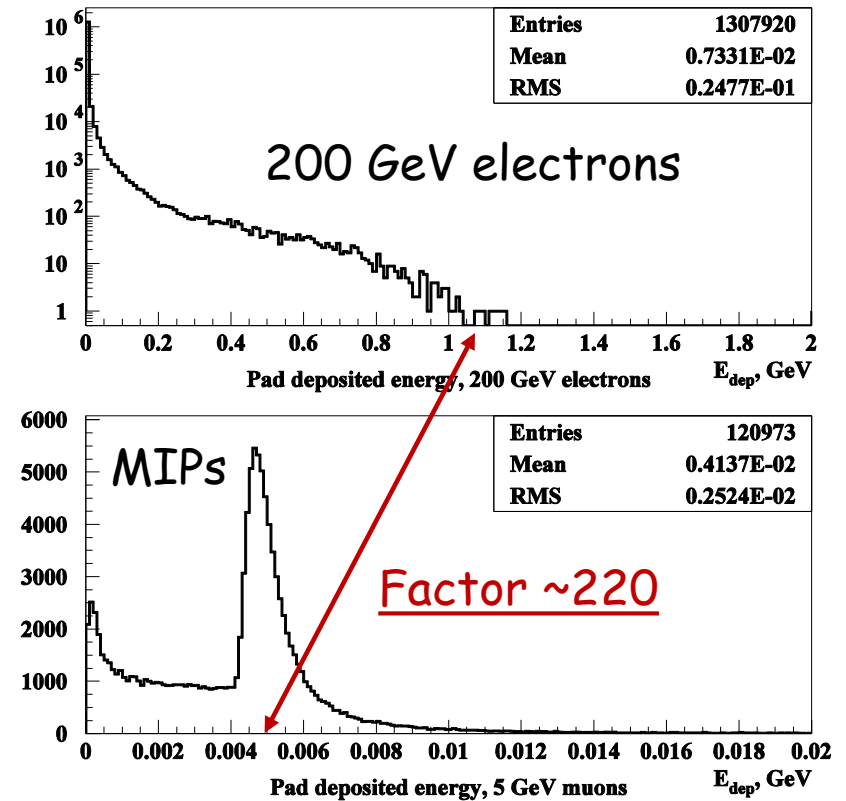
Dynamic range needed for Readout



Baseline design



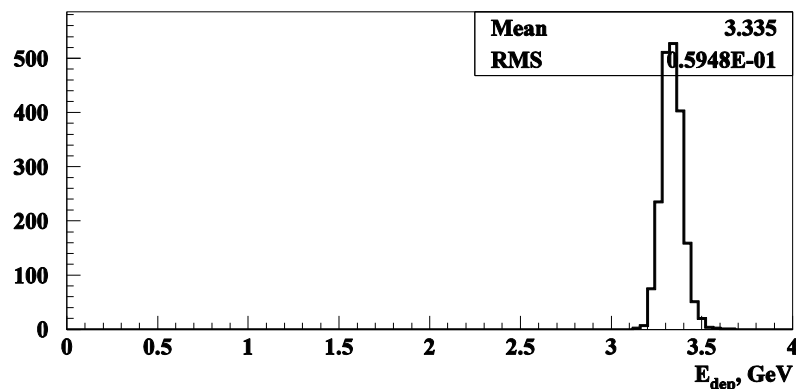
New sapphire design



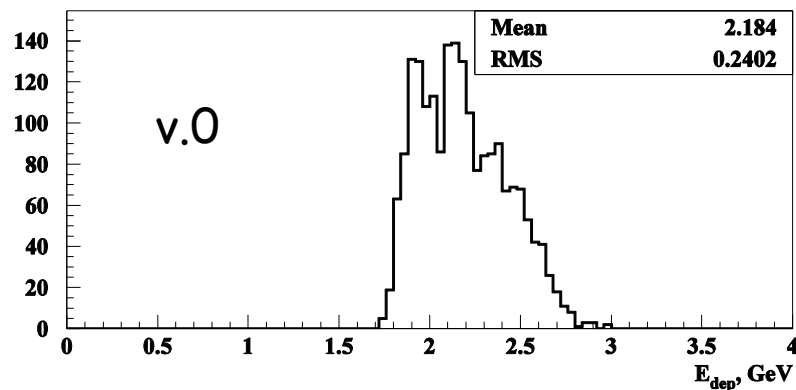
BeamCal energy resolution



200 GeV electrons, GEANT3 Monte Carlo

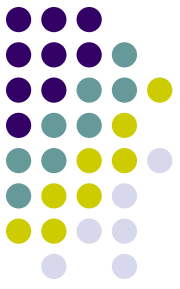


Baseline design.
 $\delta E/E = 1.6\%$



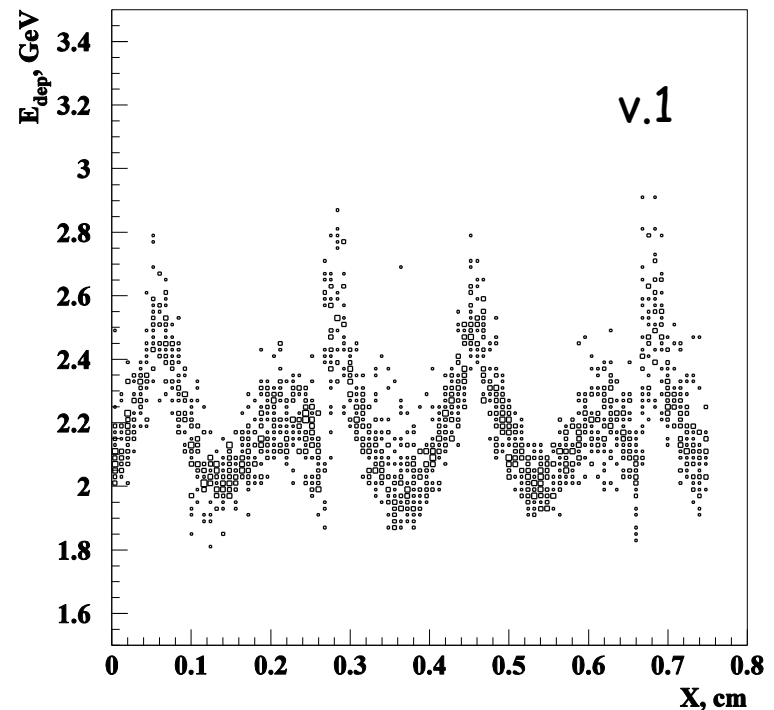
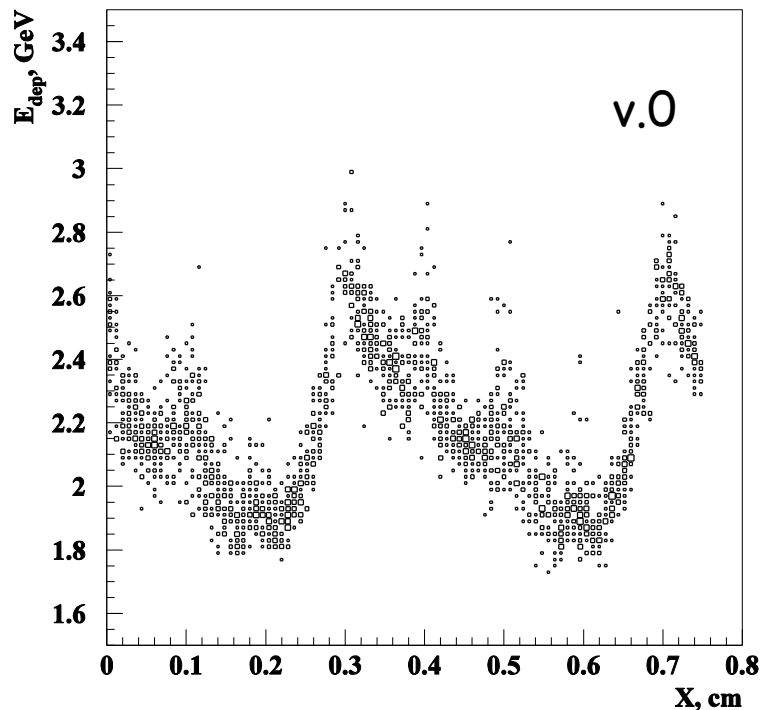
New design.
 $\delta E/E \sim 11\%$
Nonuniform response!

New design. Response (X) nonuniformity.



Along the strips response is uniform.

Response nonuniformity in the direction, perpendicular to the strips, depends on relative layer positioning. Further optimization is needed.

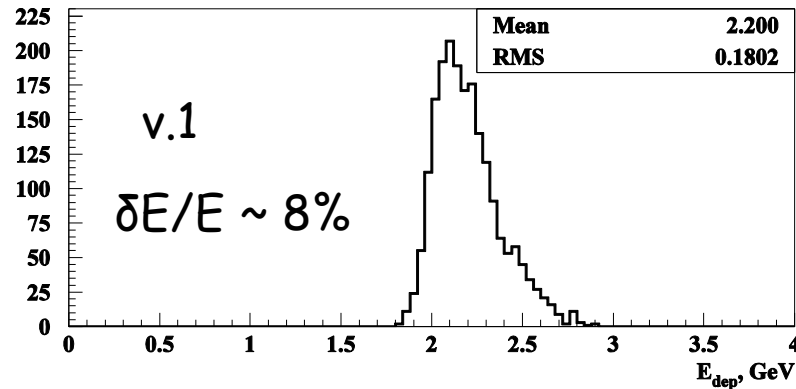
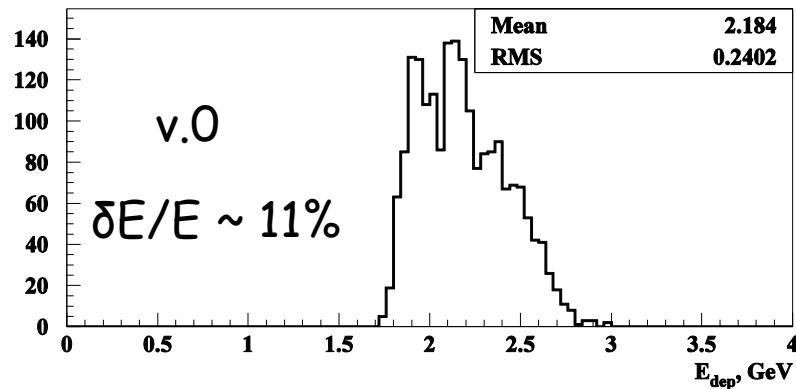
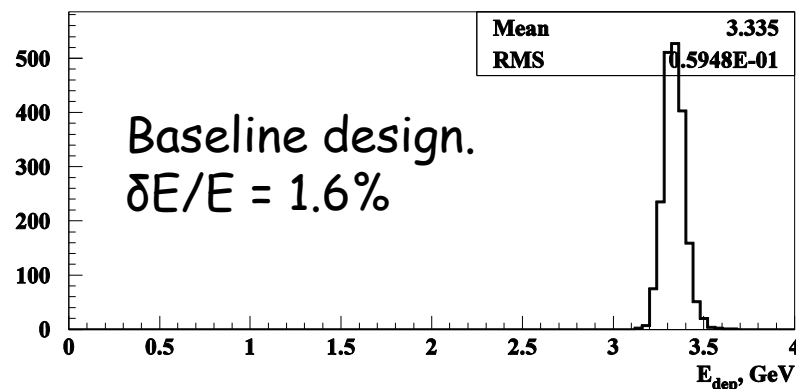
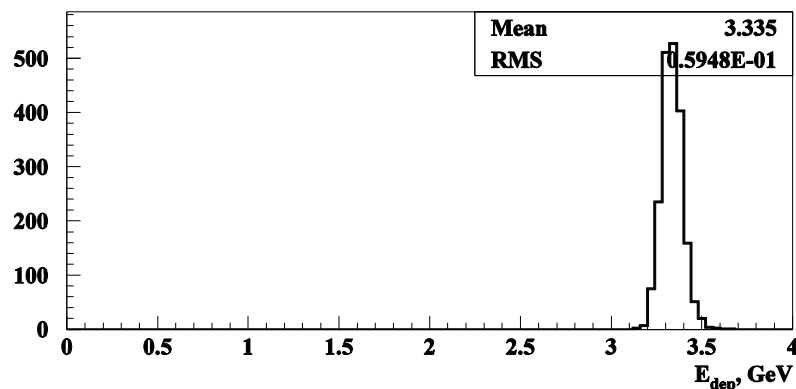


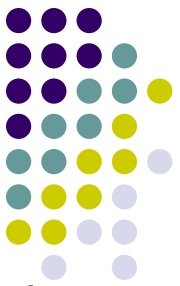
200 GeV electron showers

BeamCal energy resolution-1



200 GeV electrons, GEANT3 Monte Carlo





Conclusions and outlook

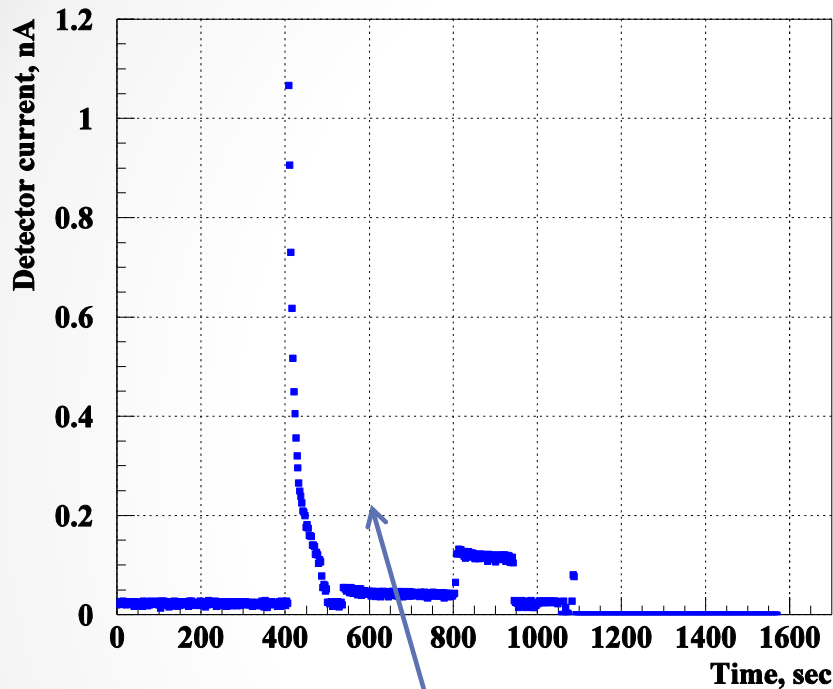
- Sapphire (single crystal Al_2O_3) is a very promising wide-bandgap material for HEP applications
- Produced in large quantities for industrial purposes, large size wafers are available (~ 25 cm, up to 40 cm diameter is possible), not expensive
- Perfect electrical properties, excellent radiation hardness, but presently low charge collection efficiency ($\sim 5\%$, probably due to high level of impurities)
- For many applications, where radiation hardness is an issue (large particle fluxes), sapphire could be used as it is, i.e. leakage current sensors, detection of particle bunches, calorimetry etc
- Sapphire detector designed for MIP detection was tested at the beam. Results will be published soon.
- Design of the ILC BeamCal, based on sapphire sensors, is presented.
- First Monte Carlo simulations show promising results.
- Further plans: optimization, prototyping, test beam measurements ...



Backup slides

Test of sapphire and quartz sensors at the 10 MeV electron beam

Quartz Crb3 Sample



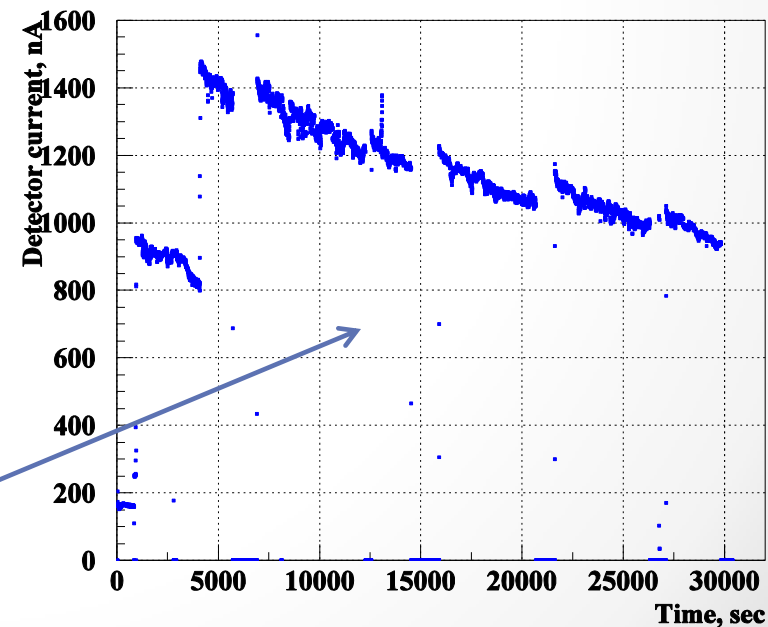
Strong polarization, seems like electric field is fully compensated.
No charge collection.

Normal charge collection

Test samples $10 \times 10 \times 0.5 \text{ mm}^3$

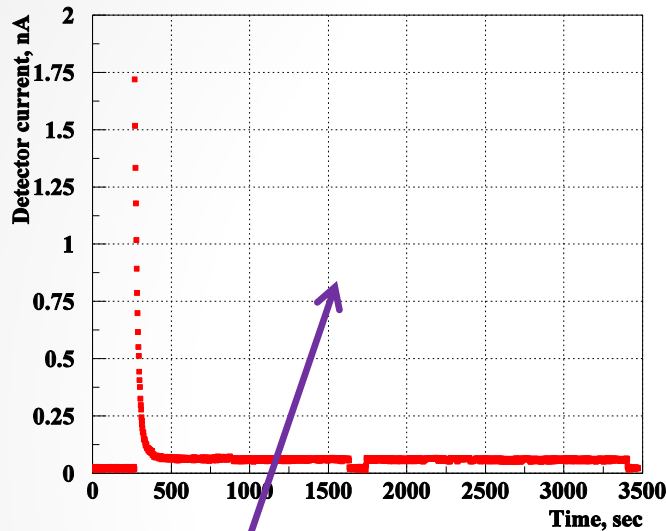
Beam current $\sim 5 \text{ nA}$

Sapphire Crb2 Sample



Test of sapphire and quartz sensors at the 10 MeV electron beam

Quartz Crb4 Sample



Silicon oxide

Aluminum oxide

Other two samples. Some recovery effect for sapphire during beam interruptions.

Sapphire Crb6 Sample

